


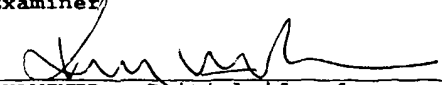


FORM PTO-1449				Atty. Docket No. XA-9387		Appln. No. 09/714,183	
LIST OF DOCUMENTS CITED BY APPLICANT				<div style="text-align: center;">  </div>			
				Applicant Hitoshi TAKEUCHI			
				Filing Date November 17, 2000		Group 2877	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
	AA						
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FOREIGN PATENT DOCUMENTS							
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	AL	59-226317	12/19/84	Japan			Partial
	AM						
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OTHER (including author, title, date, pertinent pages, etc.)							
	AR	Parity, vol. 05, No. 10, 1990-10, pp. 37-39 (with partial translation)					
	AS						
Examiner/ 				Date Considered 11/26/2003			
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FORM PTO-1449	Atty. Docket No. XA-9387	Appln. No. 09/714,183
<u>LIST OF DOCUMENTS CITED BY APPLICANT</u>		RECEIVED MAY 30 2002 TC 2800 MAIL ROOM
Applicant Hitoshi TAKEUCHI et al.		
Filing Date November 17, 2000		Group 2877

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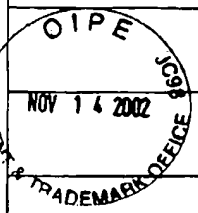


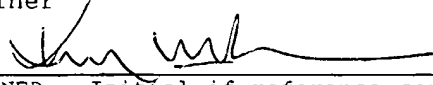
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


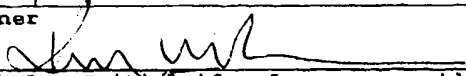
OTHER (including author, title, date, pertinent pages, etc.)

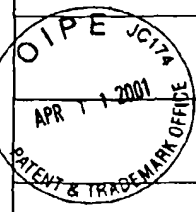
	Haig et al., "Effects of Wavefront Aberration on Visual Instrument Performance, and a Consequential Test Technique," <u>Applied Optics</u> , 2/1/87, Vol. 26, No. 3, pp. 492-500.
	Kitano et al., "Spherical Aberration of Gradient-Index Rod Lenses," <u>Applied Optics</u> , 2/83, Vol. 22, No. 3, pp. 396-399.

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				Applicant			
				Hitoshi TAKEUCHI et al.			
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November 17, 2000				2877			
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	AA	5,202,748	04/13/93	MacDonald et al.	356	360	
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OTHER (including author, title, date, pertinent pages, etc.)							
	AR	Gourlay et al., "A real-time closed-loop liquid crystal adaptive optics system: first results", <u>Optics Communications</u> , Vol. 137, No. 1-3, April 15, 1997, pp. 17-21.					
	AS						
	AT						
Examiner 				Date Considered 11/26/2003			
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				Filing Date November 17, 2000		Group 2877	
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Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
	AA	3,973,953	8/10/76	Montgomery	96	1	
	AB	4,405,232	9/20/83	Mansell	356	121	
	AC	4,413,909	11/8/83	Pohle	356	354	
	AD	4,438,330	3/20/84	Hardy	250	201	
	AE	4,620,790	11/4/86	Hufnagel	356	124	
	AF	4,667,103	5/19/87	Watson et al.	250	332	
	AG	4,725,138	2/16/88	Wirth et al.	356	121	
	AH	5,294,971	3/15/94	Braunecker et al.	356	121	
	AI	5,300,766	4/5/94	Granger et al.	250	201.9	
	AJ	6,052,180	4/18/00	Neal et al.	356	121	
	AK	6,130,419	10/10/00	Neal	250	201.9	
		AL	6,184,974	2/6/01	Neal et al.	356	121
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OTHER (including author, title, date, pertinent pages, etc.)							
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				Hitoshi TAKEUCHI			
				Filing Date	Group		
				November 17, 2000	2877		
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Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
<i>DM</i>	AA	5,680,200	10/21/97	Sugaya et al.	355	53	
	AB	5,754,299	5/19/98	Sugaya et al.	356	401	
	AC	5,825,476	10/20/98	Abitol et al.	356	124	
	AD	5,233,174	8/3/93	Zmek	250	201.9	
	AE	5,864,381	1/26/99	Neal et al.	351	205	
	AF	5,936,720	8/10/99	Neal et al.	356	121	
	AG	5,493,391	2/20/96	Neal et al.	356	121	
	AH	4,737,621	4/12/88	Gonsiorowski et al.	250	201	
	AI	4,490,039	12/25/84	Bruckler et al.	356	121	
	AJ	5,629,765	5/13/97	Schmutz	356	121	
<i>DM</i>	AK	5,912,731	6/15/99	DeLong et al.	356	121	
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Examiner Initial		Document Number	Date	Country	Class	Sub-Class	Translation
<i>DM</i>	AL	2-238338	9/20/90	Japan			Yes
	AM	9-49781	2/18/97	Japan			No
	AN	10-92722	4/10/98	Japan			No
<i>DM</i>	AO	0 833 193 A	1/4/98	Europe			
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FORM PTO-1449

Atty. Docket No.

Appln. No.

XA-9387

09/714,183

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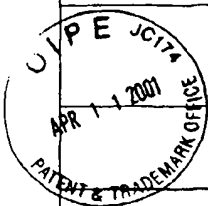
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Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
<i>QW</i>	AA	6,052,180	4/18/00	Neal et al.	356	121	
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